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[73] Assignee: Intel Corporation, Santa Clara, Calif.

[21] Appl. No.: 876,117

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### Related U.S. Application Data

- [63] Continuation of Ser. No. 699,490, Aug. 19, 1996, abandoned.
- [51] Int. Cl.<sup>6</sup> Int. Cl. 6 2006:01/01 and Int. Cl. 6 2006:01/02 G11C 16/06
- [52] U.S. Cl. U.S. Cl. 2006:01/01 and U.S. Cl. 2006:01/02 365/185.21; 365/185.26;  
365/185.12; 365/185.13; 365/185.03
- [58] Field of Search U.S. Cl. 2006:01/01 and U.S. Cl. 2006:01/02 365/185.21, 185.26,  
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## ABSTRACT

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A method for determining data stored by a memory cell. The memory cell has a select gate coupled to a wordline, a first electrode coupled to a bitline, and a second electrode coupled to a conductor. The method comprises: floating the bitline; applying a first voltage to the wordline; applying a second voltage to the conductor such that the bitline is set to a third voltage that is equal to the first voltage minus a threshold voltage of the memory cell; and sensing the third voltage to determine the data stored by the memory cell.

**18 Claims, 8 Drawing Sheets**

